

**Search Notes**

Application/Control No.

10/695,476

Examiner

M. Lee

Applicant(s)/Patent under  
Reexamination

DESCH, DAVID ALAN

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	725, 726, 731-733, 553-558	11/23/2006	ML
375	316		
725	151		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference search history printout		11/23/2006	ML

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/23/2006	ML